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ABSTRACT OF THE DISCLOSURE

Systems and methods of the present invention measure at least one reflecting surface of an object disposed along an optical path. In some embodiments a measured optical interference signal for each of at least three wavelengths of reflected light may be used to determine a modulation of frequency components of a Fourier series. Frequency components of a Fourier series may be transformed to spatial components that describe intensities and positions of light reflected along an optical path.

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Systems and methods of the present invention permit rapid measuring and may monitor corneal thickness during surgery. The invention may do so by integrating an ablation device and a measurement apparatus into a single system. An integrated scanning and monitoring system may include an ablative light source producing an ablative beam and a measurement light source producing a measurement beam.